

<i>Search Notes</i>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10565106	HAN ET AL.
	Examiner	Art Unit
	M. Lee	2622

SEARCHED

Class	Subclass	Date	Examiner
348	515, 518, 484	2/19/09	ml

SEARCH NOTES

Search Notes	Date	Examiner
east	2/19/09	ml

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

	/M. Lee/ Primary Examiner, Art Unit 2622
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